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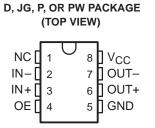
- Operates From a Single 5-V Supply
- 0 to 5 V Common-Mode Input Voltage Range
- Self-Biased Inputs
- Complementary 3-State Outputs
- Enable Capability
- Hysteresis . . . 5 mV Typ
- Response Times . . . 25 ns Typ

description

The TL712 is a high-speed comparator fabricated with bipolar Schottky process technology. The circuit has differential analog inputs and complementary 3-state TTL-compatible logic outputs with symmetrical switching characteristics. When the output enable, (OE), is low, both outputs are in the high-impedance state. This device operates from a single 5-V supply and is useful as a disk memory read-chain data comparator.

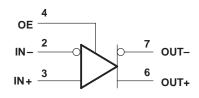
The TL712 is characterized for operation from 0° C to 70° C.

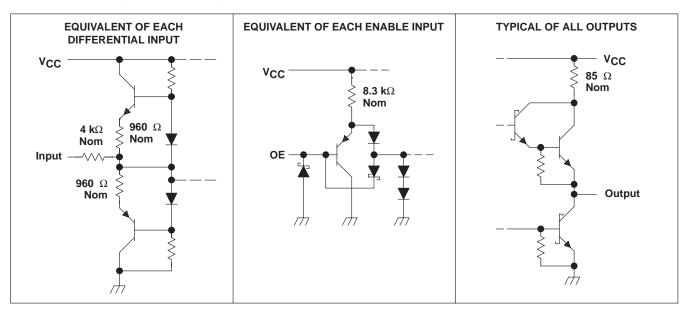
schematics of inputs and outputs



NC-No internal connection

symbol (positive logic)





PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Input voltage, V _I , any differential input±25 V Differential input voltage, V _{ID} (see Note 2)±25 V	
Enable input voltage	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the "recommended operating conditions" section of this specification is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltage values, except differential voltages, are with respect to the network ground.

2. Differential voltage values are at IN+ with respect to IN-.

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
Common-mode input voltage, VIC	0		5	V
High-level output current, IOH			-1	mA
Low-level output current, IOL			16	mA
Operating free-air temperature, T _A	0		70	°C

electrical characteristics at V_{CC} = 5 V, T_A = 25° C

	PARAMETER TEST CONDITIONS				MAX	UNIT
VT	Threshold voltage (VT + and VT –)	$V_{ICR} = 0$ to 5 V	-100‡		100	mV
V _{hys}	Hysteresis ($V_{T+} - V_{T-}$)			5		mV
VOH	High-level output voltage	$V_{ID} = 100 \text{ mV}, \qquad I_{OH} = -1 \text{ mA}$	2.7	3.5		V
VOL	Low-level output voltage	$V_{ID} = -100 \text{ mV}, I_{OL} = 16 \text{ mA}$		0.4	0.5	V
IOZ	Off-state output current	V _O = 2.4 V			-20	μA
Ц	Enable current	V _I = 5.5 V			100	μA
ΠΗ	High-level enable current	V _{IH} = 2.7 V			20	μA
Ι _{ΙL}	Low-level enable current	V _{IL} = 0.4 V			-360	μA
r _i	DIfferential input resistance		4			kΩ
r _o	Output resistance				100	W
los	Short-circuit output current		-15		-85	mA
ICC	Supply current	V _{ID} = 0, No load		17	20	mA

[‡] The algebraic convention, where the more negative limit is designated as minimum, is used in this data sheet for input threshold voltage levels only.

switching characteristics, V_{CC} = 5 V, T_A = 25° C

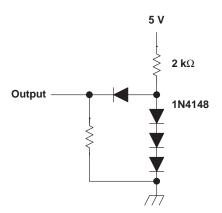
PARAMETER			TEST CONDITIONS			TYP	MAX	UNIT	
^t PLH	Propagation delay time, low-to-high-level output	TTL load,	TTL load	See Figure 1,	See Note 3		25		ns
^t PHL	Propagation delay time, high-to-low-level output		TE load, See Figure 1,	See Note 3		25		ns	

NOTE 3: The response time specified is for a 100-mV input step with 5-mV overdrive (105 mV total), and is the interval between the input step function and the instant when the output crosses 2.5 V.



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PARAMETER MEASUREMENT INFORMATION





TYPICAL CHARACTERISTICS

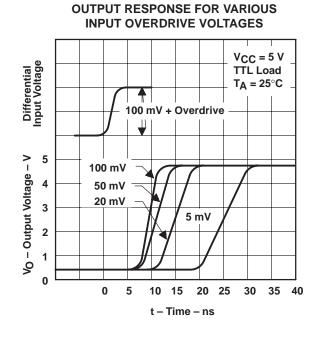


Figure 2

OUTPUT RESPONSE FOR VARIOUS INPUT OVERDRIVE VOLTAGES

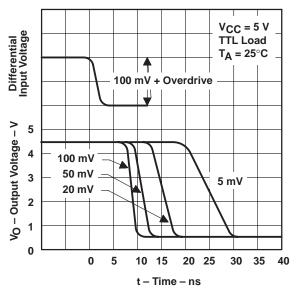
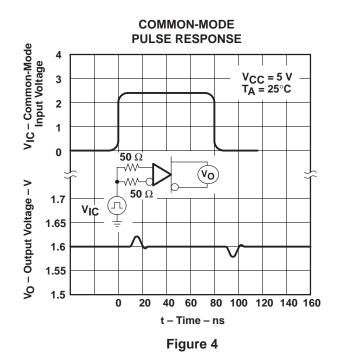


Figure 3



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TYPICAL CHARACTERISTICS



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